

## The Usage of Backscattered Electrons in Scanning Electron Microscopy

Pavel Kejzlar<sup>1</sup>, Martin Švec<sup>2</sup>, Eva Macajová<sup>2</sup>

<sup>1</sup>Institute for Nanomaterials, Advanced Technologies and Innovation, Technical University of Liberec. Studentska 1402/2, 461 17 Liberec. Czech Republic. E-mail: pavel.kejzlar@tul.cz

<sup>2</sup>Department of Materials Science, Technical University of Liberec, Studentska 1402/2, Liberec, Czech Republic. E-mail: martin.svec@tul.cz; eva.macajova@tul.cz

**Secondary and backscattered electrons are the most common signals used for imaging in the scanning electron microscopy. Generally, SE are used to obtain topographical contrast while BSE show differences in chemical composition (so called Z-contrast). The aim of the present work is to show possibilities and techniques to obtain not-so-common information using BSE, as e.g. orientation contrast, residual stress, different allotropic modifications, etc.**

**Keywords:** Scanning Electron Microscopy, BSE, Structure.

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